

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:

5962-87804	01	B	X
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device type. The device type shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	54AS21	Dual 4-input positive AND gate

1.2.2 Case outlines. The case outline shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
B	F-3 (14-lead, 3/16" x 1/4"), flat package
C	D-1 (14-lead, 1/4" x 3/4"), dual-in-line package
D	F-2 (14-lead, 1/4" x 3/8"), flat package
2	C-2 (20-terminal, .350" x .350"), square chip carrier package

1.3 Absolute maximum ratings.

Supply voltage range	-0.5 V dc to +7.0 V dc
Input voltage range	-1.5 V dc at -18 mA to +7.0 V dc
Storage temperature	-65°C to +150°C
Maximum power dissipation (P_D) per device ^{1/}	66 mW
Lead temperature (soldering, 10 seconds)	+300°C
Thermal resistance, junction-to-case (θ_{JC}):	
Cases B, C, and D-	See MIL-M-38510, appendix C
Case 2	80°C/W ^{2/}
Junction temperature (T_J)	+175°C

1.4 Recommended operating conditions.

Supply voltage (V_{CC})	4.5 V dc minimum to 5.5 V dc maximum
Minimum high level input voltage (V_{IH})	2.0 V dc
Maximum low level input voltage (V_{IL})	0.8 V dc
Case operating temperature range (T_C)	-55°C to +125°C

^{1/} Must withstand the added P_D due to short circuit test (e.g., I_{OS}).

^{2/} When a thermal resistance for this case is specified in MIL-M-38510, appendix C, that value shall supersede the value specified herein.

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE A	CODE IDENT. NO. 14933	DWG NO. 5962-87804
		REV	PAGE 2

2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections and logic diagram. The terminal connections and logic diagram shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE A	CODE IDENT. NO. 14933	DWG NO. 5962-87804
		REV	PAGE 3

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C < T _C < +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
Low level output voltage	V _{OL}	V _{CC} = 4.5 V, I _{OL} = 20 mA V _{IN} = 0.8 V or 2.0 V	1,2,3		.5	V
High level output voltage	V _{OH}	V _{CC} = 4.5 V, I _{OH} = -2 mA V _{IN} = 0.8 V or 2.0 V	1,2,3	2.5		V
Input clamp voltage	V _{IC}	V _{CC} = 4.5 V, I _{IN} = -18 mA T _C = +25°C	1		-1.2	V
High level input current	I _{IH1}	V _{CC} = 5.5 V, V _{IN} = 2.7 V	1,2,3		20	μA
	I _{IH2}	V _{CC} = 5.5 V, V _{IN} = 7.0 V	1,2,3		100	μA
Low level input current	I _{IL}	V _{CC} = 5.5 V, V _{IN} = 0.4 V	1,2,3		-500	μA
Short circuit output current	I _O	V _{CC} = 5.5 V, V _{OUT} = 2.25 V 1/	1,2,3	-30	-112	mA
Supply current	I _{CCH}	V _{CC} = 5.5 V, V _{IN} = 4.5 V	1,2,3		4.6	mA
	I _{CCL}	V _{CC} = 5.5 V, V _{IN} = 0.0 V	1,2,3		12	mA
Functional tests		See 4.3.1c	7			
Propagation delay time, A, B, C, or D to Y	t _{PLH}	V _{CC} = 5.0 V, R _L = 500Ω C _L = 50 pF	9	1	7	ns
	t _{PHL}		10,11	1	10	ns

1/ The output conditions have been chosen to produce a current that closely approximates one-half of the true short circuit output current, I_{OS}.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

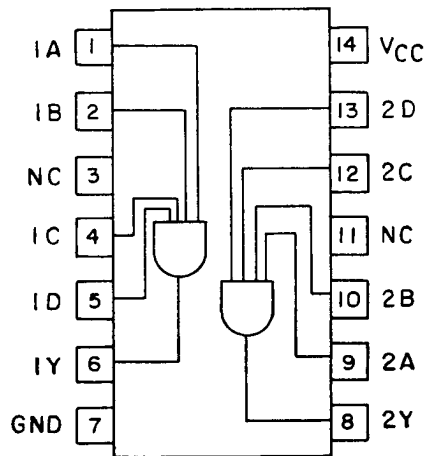
3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE A	CODE IDENT. NO. 14933	DWG NO. 5962-87804
		REV	PAGE 4

Cases B, C and D



Case 2

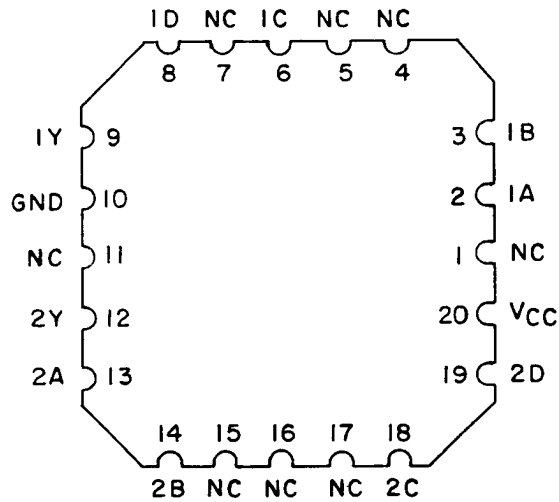


FIGURE 1. Terminal connections and logic diagram.

MILITARY DRAWING

DEFENSE ELECTRONICS SUPPLY CENTER
DAYTON, OHIO

SIZE

A

CODE IDENT. NO.

14933

DWG NO.

5962-87804

REV

PAGE

5

Inputs				Output
A	B	C	D	Y
H	H	H	H	H
L	X	X	X	L
X	L	X	X	L
X	X	L	X	L
X	X	X	L	L

FIGURE 2. Truth table.

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE	CODE IDENT. NO.	DWG NO.
	A	14933	5962-87804
	REV		PAGE 6

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test (method 1015 of MIL-STD-883).

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2) $T_A = +125^{\circ}\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroup 7 tests shall verify the truth table.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test (method 1005 of MIL-STD-883) conditions:

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2) $T_A = +125^{\circ}\text{C}$, minimum.

(3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*,2,3,9
Group A test requirements (method 5005)	1,2,3,7,9, 10,11
Groups C and D end-point electrical parameters (method 5005)	1,2,3

*PDA applies to subgroup 1.

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE A	CODE IDENT. NO. 14933	DWG NO. 5962-87804
	REV		PAGE 7

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number ^{1/}
5962-8780401BX	01295	SNJ54AS21WA
5962-8780401CX	01295	SNJ54AS21J
5962-8780401DX	01295	SNJ54AS21W
5962-87804012X	01295	SNJ54AS21FK

^{1/} Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
number

01295

Vendor name
and address

Texas Instruments, Inc.
P.O. Box 6448
Midland, TX 79701

MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO	SIZE A	CODE IDENT. NO. 14933	DWG NO. 5962-87804
	REV		PAGE 8

DESC FORM 193A
FEB 86

011342 ✓ - -